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Poster Session





Innovative Ground Block Pin Design for Improved High-Frequency Test Performance over a Conventional Ground Block Approach

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Introduction

With the growth of electronic products that require wireless connection such as mobile and IoT, there is continuous demand for many high frequency devices.



- High-performance sockets for testing such high-frequency devices are indispensable to ensure product reliability. For reliable testing, it is necessary to ensure stable contact between the pin and the device, but oxides and foreign matter affect test stability, so sockets are required to prevent them.
- Similar to the contact pin, the ground (GND) Block is susceptible to oxides and foreign matter.
- The contact properties are improved by redesigning the tip shape, however, this is not enough.



Challenges

- GND Block with scrubbing performance can be used for reliable testing of high frequency devices with less cleaning iteration.
- □ Low thermal resistance, high current capability and low load are also required.

Innovative Solution (International Patent Pending)			
GND Block Pin	Mechanical specifications		
(International Patent Pending)	Contact force	0.076±0.015N/pin	
	Contact stroke	0.06mm	
	Test height	0.4mm	
	Mechanical durability	Up to 1M insertions	
	Electrical specifications		
	Contact resistance		<0.10hm
Material: BeCu	Current rating (Total 4pins)		7.4A
Plating: NiAu	High frequency (GND 24pins)		2.96GHz

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